

U.S. DEPARTMENT OF COMMERCE U.S. PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT BY APPLICANT Form PTO-1449	Serial No.	10/758,913
	Filing Date	January 16, 2004
	Applicant	Oren Eliezer et al.
	Art Unit	2614
	Examiner	Ramnandan P. Singh
Sheet 1 of 1	Atty Docket No.	12411.0025;TI-35771

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name	Class	Subclass

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	Name	T

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Author, title, date, page(s), etc.
	1	Y. Sakinori, H. Mino, Y. Sekine, "Measurement of Phase Noise in High-Precision Oscillator Using PLL-Type Frequency Multiplier", Electronics and Communications in Japan, Part 2, Vol. 84, No. 8, pp. 64-70, 2001.
	2	M. Takamiya, H. Inohara, M. Mizuno, "On-Chip Jitter-Spectrum-Analyzer for High-Speed Digital Designs", International Solid State Circuits Conf. (ISSCC) 2004.

Examiner Signature		Date Considered	
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